Real-world issue: Voltage-sensor faults

- Sometimes systems for which we would like a state estimate have sensors with intermittent faults
- Would like to detect faulty measurements and discard them
  - Time update steps of the KF still implemented
  - Measurement update steps are skipped ($L_k = 0$)
- KF provides elegant theoretical means to accomplish this goal. Background:
  - Predicted measurement is $\hat{y}_k = C_k \hat{x}_k^- + D_k u_k$
  - Prediction covariance (uncertainty) matrix is $\Sigma_{\tilde{y},k} = C_k \Sigma_{\tilde{x},k}^- C_k^T + \Sigma_{\tilde{v}}$
  - The innovation is $\tilde{y}_k = y_k - \hat{y}_k$

Measurement validation gating

- Can place “measurement validation gate” on measurement using normalized estimation error squared (NEES)

$$e_k^2 = \tilde{y}_k^T \Sigma_{\tilde{y},k}^{-1} \tilde{y}_k$$

- NEES e_k^2 has Chi-squared distribution with m degrees of freedom, where $y_k \in \mathbb{R}^m$
- If e_k^2 is outside of bounding value for Chi-squared distribution for a desired confidence level, then measurement is discarded
- Note: If a many measurements are discarded in short time interval, sensor may truly have failed, or state estimate and covariance may have gotten “lost”
- Is sometimes helpful to “bump up” covariance $\Sigma_{\tilde{x},k}^{\pm}$, which simulates additional process noise, to help Kalman filter to reacquire
- Both done in practice to aid robustness of a real implementation

NEES is chi-squared

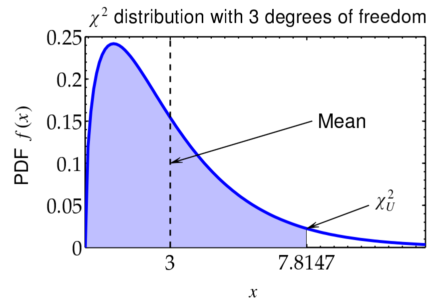
- To prove NEES is chi-squared, define $z_k = M_k \tilde{y}_k$
  - Mean of z_k is $\mathbb{E}[z_k] = \mathbb{E}[M_k \tilde{y}_k] = 0$
  - Covariance of z_k is $\Sigma_{\tilde{z},k} = \mathbb{E}[M_k \tilde{y}_k \tilde{y}_k^T M_k^T] = M_k \Sigma_{\tilde{y},k} M_k^T$
  - z_k is Gaussian (since it is a linear combination of Gaussians)
- If we define M_k such that $M_k^T M_k = \Sigma_{\tilde{y},k}^{-1}$, then
  - M_k is the lower-triangular Cholesky factor of $\Sigma_{\tilde{y},k}^{-1}$
  - Also, $z_k \sim \mathcal{N}(0, I)$ since $\Sigma_{\tilde{z},k} = M_k \left(M_k^T M_k\right)^{-1} M_k^T = M_k M_k^{-1} M_k^{-T} M_k^T = I$
- NEES $e_k^2 = z_k^T z_k = \tilde{y}_k^T \Sigma_{\tilde{y},k}^{-1} \tilde{y}_k$ is the sum of squares of independent $\mathcal{N}(0,1)$ RVs
- So, e_k^2 is <u>chi-square with m degrees of freedom</u>, where m is the dimension of $\tilde{y}_k$

What does this really mean?

- e_k^2 never negative (sum of squares); pdf also asymmetric
- pdf of chi-square RV X having m degrees of freedom is

$$f_X(x) = \frac{1}{2^{m/2}\Gamma(m/2)} x^{(m/2-1)} e^{-m/2}$$

  - Tricky, but don't need to evaluate in real time
- Instead, use value *precomputed* from pdf
- For $1-\alpha$ confidence of a valid measurement, need to find χ_U^2 such that there is α area above χ_U^2 (figure drawn for $\alpha = 0.05$)
- Discard measurement if NEES greater than χ_U^2



Computer calculation of χ_U^2

- In MATLAB (Statistics and Machine Learning Toolbox) can find χ_U^2 where inverse CDF is equal to $1-\alpha$

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X2U = chi2inv(1-0.01,2) % Upper critical value X2U = 9.2103
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  - Function "chi2inv" is built in to Octave
- Note that χ_U^2 needs to be computed once only, offline
  - Based only on m and α, so doesn't need to be recalculated as KF runs
- For hand calculations a χ^2-table is available on next page
- If $e_k^2 > \chi_U^2$, then measurement is discarded ($L_k = 0$); else, measurement kept

Manual table-lookup of χ_U^2

- For chi-squared distribution with m degrees of freedom, table entries list values of $\chi_U^2(\alpha, m)$ for specified upper tail area α

Degrees of	Upper tail areas α					
freedom m	0.25	0.10	0.05	0.025	0.01	0.005
1	1.323	2.706	3.841	5.024	6.635	7.879
2	2.773	4.605	5.991	7.378	9.210	10.597
3	4.108	6.251	7.815	9.348	11.345	12.838
4	5.385	7.779	9.488	11.143	13.277	14.860
5	6.626	9.236	11.070	12.833	15.086	16.750
6	7.841	10.645	12.592	14.449	16.812	18.548

Summary

- KF has built-in mechanism that enables detecting voltage-sensor errors
- Once only, off-line, precompute $\chi^2_U(\alpha, m)$ for $y_k \in \mathbb{R}^m$ and desired α
- As KF executes, every time sample, compute $e_k^2 = \tilde{y}_k^T \Sigma_{\tilde{y},k}^{-1} \tilde{y}_k$
  - If $e_k^2 > \chi^2_U(\alpha, m)$, then discard measurement (set $L_k = 0$)
  - Otherwise, apply measurement update as usual
- If many sequential measurements discarded, consider "bumping up" covariance as $\Sigma_{\tilde{x},k}^+ = Q\,\Sigma_{\tilde{x},k}^+$ where $Q > 1$
- If problems persist, likely a permanent sensor fault